

ABSTRACT

Test Probe Device

The invention relates to a test probe device (1) for making electrical contact with an in particular multi-pole contact partner, with a carrier part (2), which has at least one guide opening (4), and with at least one test probe (5), which is longitudinally displaceably mounted in the guide opening (4), wherein the test probe (5) has a cylindrical housing (6) in which one or more in particular pin-shaped contact elements (7) are arranged, each of which have a contact end (8) for making contact with the contact partner, wherein the housing (6) has a guide portion (11) longitudinally displaceably mounted in the guide opening (4) and a contact portion (9) spaced apart therefrom, and wherein the contact ends (8) are assigned to the contact portion (9), wherein a spring element (10) is pretensioned between the contact portion (9) and the carrier part (2) and, adjoining the guide portion (11) at the housing (6), on the side of the carrier part (2) facing away from the spring element (10), an axial stop (12) is formed, which interacts with the carrier part (2) against the spring force of the spring element (10), wherein a maximum rotational and/or tilting angle of the test probe (5) is limited relative to the carrier part (2) by the guide opening (4) and the guide portion (11), for the purpose of which the guide opening (4) and the guide portion (11) in each case have a cross section with at least one straight line, in particular in each case a polygonal cross section, and wherein guide portion (11) and guide opening (4) are formed in such a way that the test probe (5) can tumble in at least one sliding position relative to the carrier part (2). It is provided that a transfer portion (17) is formed between the guide portion (11) and the axial stop (12), that the transfer portion (17) has a circular cross section, the diameter of which is at most as large as the smallest diagonal of the cross section of the guide opening (4) on the one hand and smaller than the largest diagonal and larger than the smallest diagonal of the cross section of the guide portion (11) on the other hand, so that the transfer portion (17), when viewed over its circumference, radially projects beyond the guide portion (11) only in some regions.

FIG. 3